

## Product description

# PointProbe® Plus ZEISS Veritekt

## Microscopes - Contact Mode Low Force

### Constant - Reflex Coating

The PointProbe® Plus (PPP) combines high application versatility and compatibility with most commercial SPMs. The typical AFM tip radius of less than 7 nm and the minimized variation in AFM tip shape provide reproducible images and enhanced resolution.

For owners of a Zeiss Veritekt or Seiko Instruments microscope using contact mode we recommend **NANOSENSORS™ PPP-ZEILR** (Zeiss Veritekt / low force constant). Compared to the contact mode AFM probe (CONT) the force constant is slightly increased.

### The AFM probe offers unique features:

- guaranteed AFM tip radius of curvature < 10 nm
- AFM tip height 10 - 15 µm
- highly doped silicon to dissipate static charge
- Al coating on detector side of AFM cantilever
- high mechanical Q-factor for high sensitivity

The reflective coating is an approximately 30 nm thick aluminium coating on the detector side of the AFM cantilever which enhances the reflectivity of the laser beam by a factor of about 2.5. Furthermore it prevents light from interfering within the AFM cantilever. As the coating is nearly stress-free the bending of the AFM cantilever due to stress is less than 2 degrees.

This AFM probe features alignment grooves on the back side of the holder chip. These grooves fit to the NANOSENSORS Alignment Chip.

### Cantilever data:

Property	Nominal Value	Specified Range
Resonance Frequency [kHz]	27	19 - 35
Force Constant [N/m]	1.6	0.6 - 3.9
Length [ $\mu\text{m}$ ]	450	440 - 460
Mean Width [ $\mu\text{m}$ ]	55	47.5 - 62.5
Thickness [ $\mu\text{m}$ ]	4	3 - 5

### Order codes and shipping units:

Order Code	AFM probes per pack	Data sheet
PPP-ZEILR-10	10	of all probes
PPP-ZEILR-20	20	of all probes
PPP-ZEILR-50	50	.....
PPP-ZEILR-W	380	of up to 32 probes